Abstract of the Disclosure:

To trim interface devices on semiconductor devices, such as trimmable output drivers and terminations, a measurement current produced in the test apparatus is impressed onto the interface device, and a measurement voltage produced by the measurement current in the interface device is detected by a trimming unit provided within the semiconductor device and is trimmed using control elements and trimming registers controlled by the trimming unit. To this end, the trimming unit ascertains trimming information which is stored in nonvolatile fashion in a memory unit in the semiconductor device and is loaded into the trimming registers in the semiconductor device whenever the semiconductor device is started up.

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